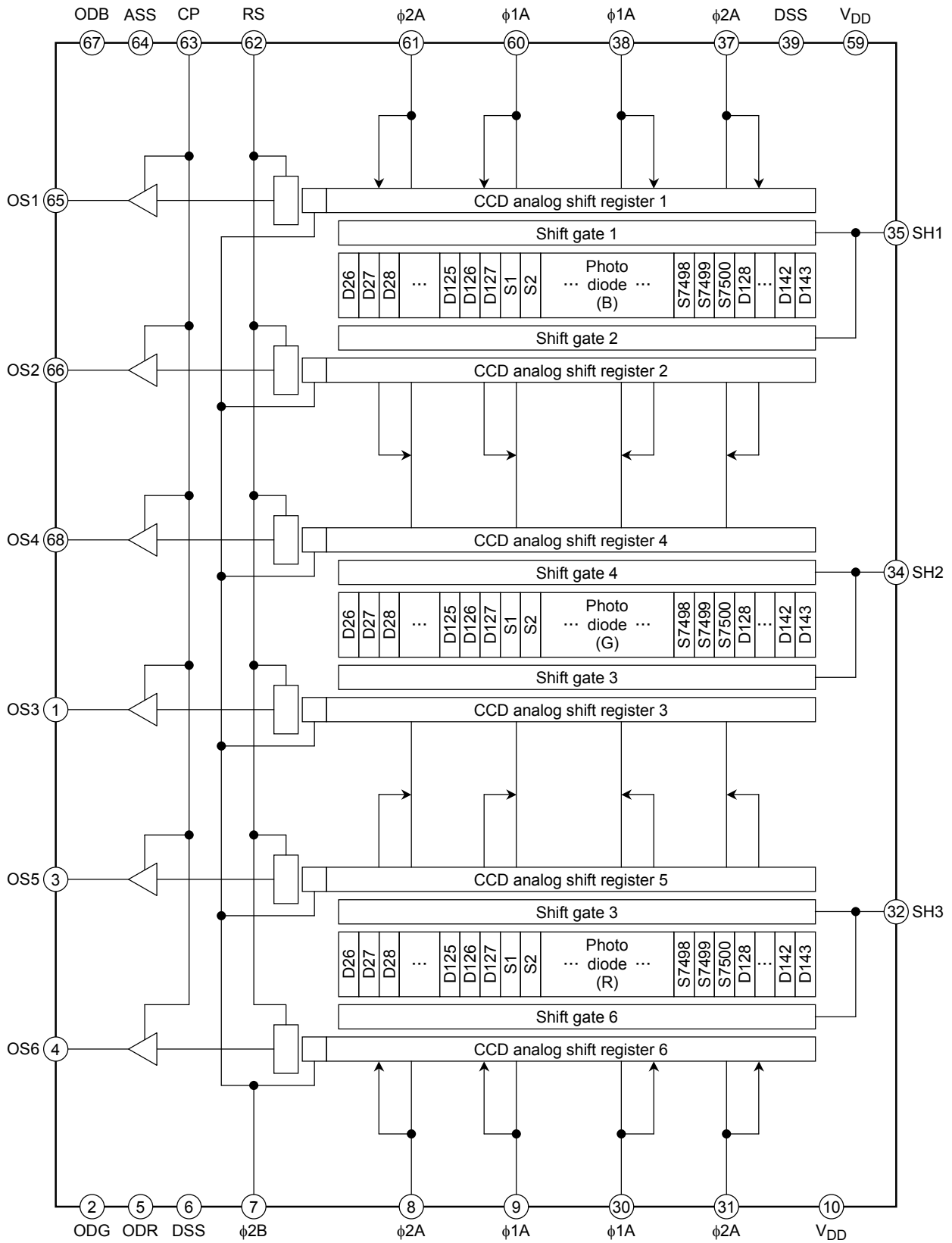


Circuit Diagram



Pin Names

Pin No.	Symbol	Name	Pin No.	Symbol	Name
1	OS3	Output signal 3 (green)	35	SH1	Shift gate 1
2	ODG	Power supply (green)	36	NC	No connect
3	OS5	Output signal 5 (red)	37	ϕ 2A	Transfer clock (phase 2)
4	OS6	Output signal 6 (red)	38	ϕ 1A	Transfer clock (phase 1)
5	ODR	Power supply (red)	39	DSS	Ground (digital)
6	DSS	Ground (digital)	40	NC	No connect
7	ϕ 2B	Last stage clock (phase 2)	41	NC	No connect
8	ϕ 2A	Transfer clock (phase 2)	42	NC	No connect
9	ϕ 1A	Transfer clock (phase 1)	43	NC	No connect
10	V _{DD}	Power supply (digital)	44	NC	No connect
11	NC	No connect	45	NC	No connect
12	NC	No connect	46	NC	No connect
13	NC	No connect	47	NC	No connect
14	NC	No connect	48	NC	No connect
15	NC	No connect	49	NC	No connect
16	NC	No connect	50	NC	No connect
17	NC	No connect	51	NC	No connect
18	NC	No connect	52	NC	No connect
19	NC	No connect	53	NC	No connect
20	NC	No connect	54	NC	No connect
21	NC	No connect	55	NC	No connect
22	NC	No connect	56	NC	No connect
23	NC	No connect	57	NC	No connect
24	NC	No connect	58	NC	No connect
25	NC	No connect	59	V _{DD}	Power supply (digital)
26	NC	No connect	60	ϕ 1A	Transfer clock (phase 1)
27	NC	No connect	61	ϕ 2A	Transfer clock (phase 2)
28	NC	No connect	62	RS	Reset gate
29	NC	No connect	63	CP	Clamp gate
30	ϕ 1A	Transfer clock (phase 1)	64	ASS	Ground (analog)
31	ϕ 2A	Transfer clock (phase 2)	65	OS1	Output signal 1 (blue)
32	SH3	Shift gate 3	66	OS2	Output signal 2 (blue)
33	NC	No connect	67	ODB	Power supply (blue)
34	SH2	Shift gate 2	68	OS4	Output signal 4 (green)

Optical/Electrical Characteristics (bit clamp)

($T_a = 25^\circ\text{C}$, $V_{OD} = V_{DD} = 11\text{ V}$, $V_\phi = V_{RS} = V_{SH} = V_{CP} = 5\text{ V (pulse)}$, $f_\phi = 1\text{ MHz}$,
 load resistance = $100\text{ k}\Omega$, t_{INT} (integration time) = 10 ms ,
 light source = A light source + CM500S filter ($t = 1.0\text{ mm}$))

Characteristics		Symbol	Min	Typ.	Max	Unit	Note
Sensitivity	Red	R (R)	7.9	11.4	14.9	V/lx·s	(Note 2)
	Green	R (G)	10.7	15.4	20.1		
	Blue	R (B)	4.2	6.1	8.0		
Photo response non uniformity		PRNU (1)	—	10	20	%	(Note 3)
		PRNU (3)	—	3	12	mV	(Note 4)
Saturation output voltage		V_{SAT}	1.0	1.5	—	V	(Note 5)
Saturation exposure		SE	0.05	0.1	—	lx·s	(Note 6)
Dark signal voltage		V_{DRK}	—	3	6	mV	(Note 7)
Dark signal non uniformity		DSNU	—	8	12	mV	(Note 8)
Dc power dissipation		P_D	—	900	1300	mW	—
Total transfer efficiency		TTE	92	98	—	%	—
Output impedance		Z_O	—	0.2	0.5	k Ω	—
Dc signal output voltage		V_{OS}	4.5	6.0	7.5	V	(Note 9)
Random noise		$N_{D\sigma}$	—	1.0	—	mV	(Note 10)

Note 2: Sensitivity is defined for each color of signal outputs average when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature.

Note 3: PRNU (1) is defined for each color on a single chip by the expressions below when the photosensitive surface is applied with the light of uniform illumination and uniform color temperature.

$$PRNU (1) = \frac{\Delta X}{\bar{X}} \times 100 (\%)$$

\bar{X} : Average of total signal outputs

ΔX : The maximum deviation from \bar{X} .

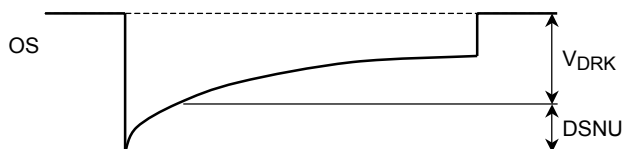
Note 4: PRNU (3) is defined as maximum voltage with next pixel, where measured 5% of SE (typ.).

Note 5: V_{SAT} is defined as minimum Saturation Output voltage of all effective pixels.

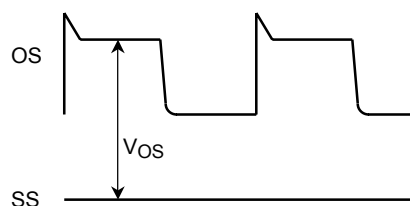
Note 6: Definition of SE: $SE = \frac{V_{SAT}}{RG}$

Note 7: V_{DRK} is defined as average dark signal voltage of all effective pixels.

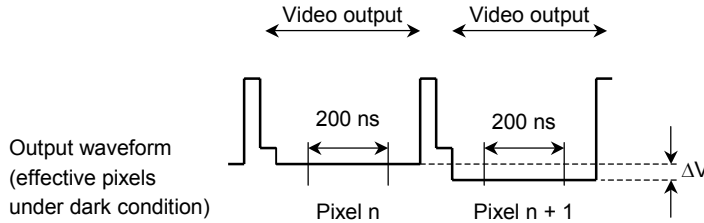
Note 8: DSNU is defined by the difference between average value (V_{DRK}) and the maximum value of the dark voltage.



Note 9: DC signal output voltage is defined as follows :



Note 10: Random noise is defined as the standard deviation (sigma) of the output level difference between two adjacent effective pixels under no illumination (i.e. dark condition) calculated by the following procedure.



- (1) Two adjacent pixels (pixel n and n + 1) in one reading are fixed as measurement points.
- (2) Each of the output levels at video output periods averaged over 200 nanosecond period to get V_n and $V_{n + 1}$.
- (3) $V_{n + 1}$ is subtracted from V_n to get ΔV .

$$\Delta V = V_n - V_{n + 1}$$
- (4) The standard deviation of ΔV is calculated after procedure (2) and (3) are repeated 30 times (30 readings).

$$\Delta V = \frac{1}{30} \sum_{i=1}^{30} |\Delta V_i| \qquad \sigma = \sqrt{\frac{1}{30} \sum_{i=1}^{30} (|\Delta V_i| - \overline{\Delta V})^2}$$

- (5) Procedure (2), (3) and (4) are repeated 10 times to get 10 sigma values.

$$\bar{\sigma} = \frac{1}{10} \sum_{j=1}^{10} \sigma_j$$

- (6) $\bar{\sigma}$ value calculated using the above procedure is observed $\sqrt{2}$ times larger than that measured relative to the ground level. So we specify the random noise as follows.

$$\text{Random noise} = \frac{1}{\sqrt{2}} \bar{\sigma}$$

Operating Condition (Ta = 25°C)

Characteristics		Symbol	Min	Typ.	Max	Unit
Clock pulse voltage	High level	$V_{\phi 1A}, V_{\phi 2A}$	4.5	5.0	5.5	V
	Low level		0	—	0.3	
Final stage clock pulse voltage	High level	$V_{\phi 2B}$	4.5	5	5.5	V
	Low level		0	—	0.3	
Shift pulse voltage (Note 11)	High level	V_{SH}	$V_{\phi} \text{ "H"} - 0.5$	$V_{\phi} \text{ "H"}$	$V_{\phi} \text{ "H"}$	V
	Low level		0	—	0.3	
Reset pulse voltage	High level	V_{RS}	4.5	5	5.5	V
	Low level		0	—	0.3	
Clamp pulse voltage	High level	V_{CP}	4.5	5	5.5	V
	Low level		0	—	0.3	
Power supply voltage		V_{OD}, V_{DD}	10.5	11.0	13.0	V

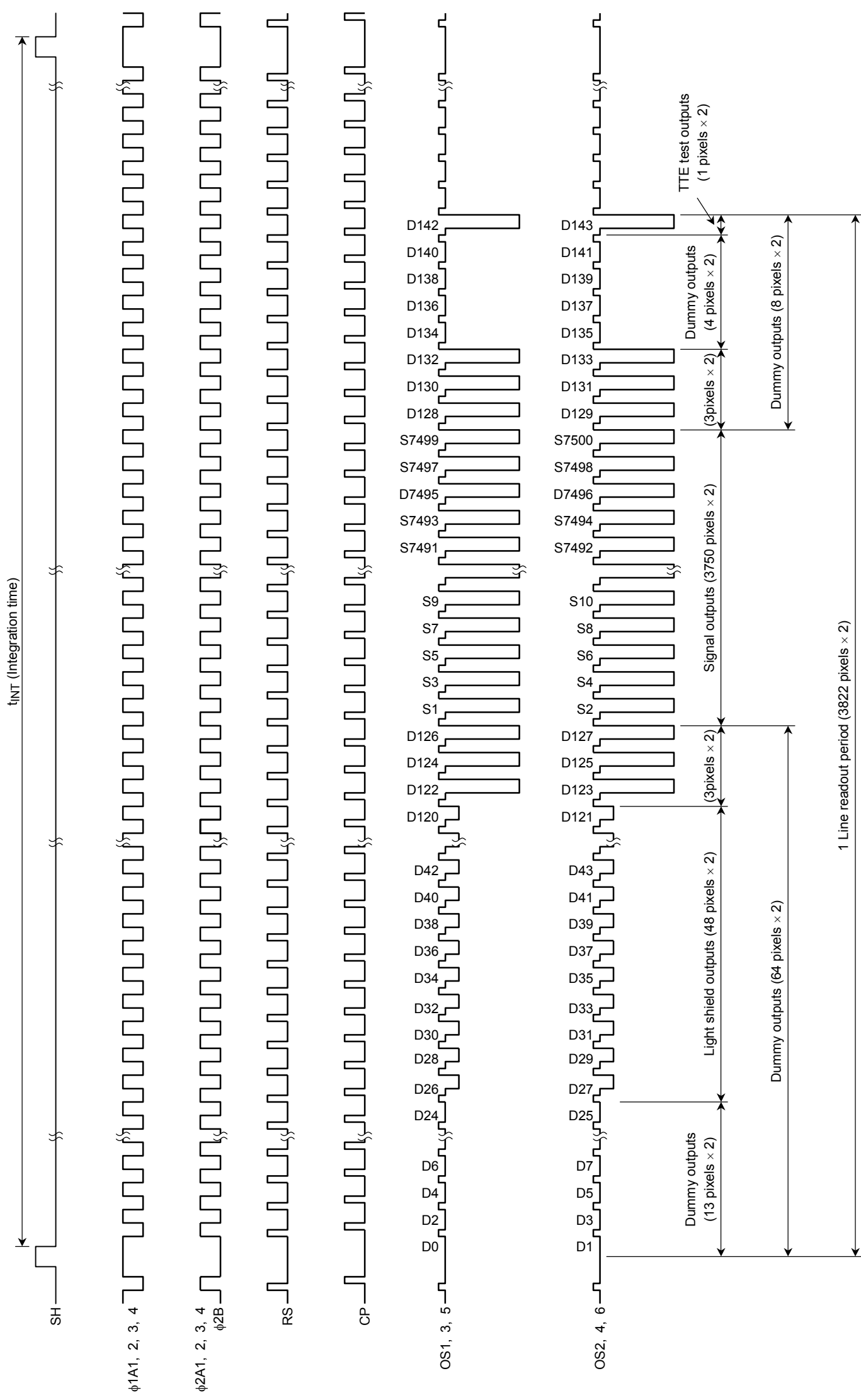
Note 11: $V_{\phi} \text{ "H"}$ means the high level voltage of $V_{\phi A}$ when SH pulse is high level.

Clock Characteristics (Ta = 25°C)

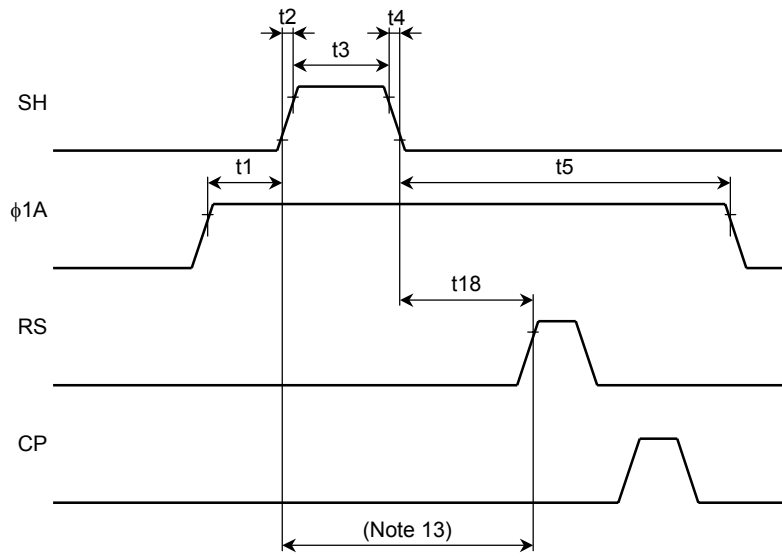
Characteristics	Symbol	Min	Typ.	Max	Unit
Clock pulse frequency	f_{ϕ}	—	1	25	MHz
Reset pulse frequency	f_{RS}	—	1	25	MHz
Clamp pulse frequency	f_{CP}	—	1	25	MHz
Clock capacitance (Note 12)	$C_{\phi A}$	—	150	—	pF
Final stage clock capacitance	$C_{\phi B}$	—	20	—	pF
Shift gate capacitance	C_{SH}	—	40	—	pF
Reset gate capacitance	C_{RS}	—	20	—	pF
Clamp gate capacitance	C_{CP}	—	20	—	pF

Note 12: $V_{OD} = 11 \text{ V}$

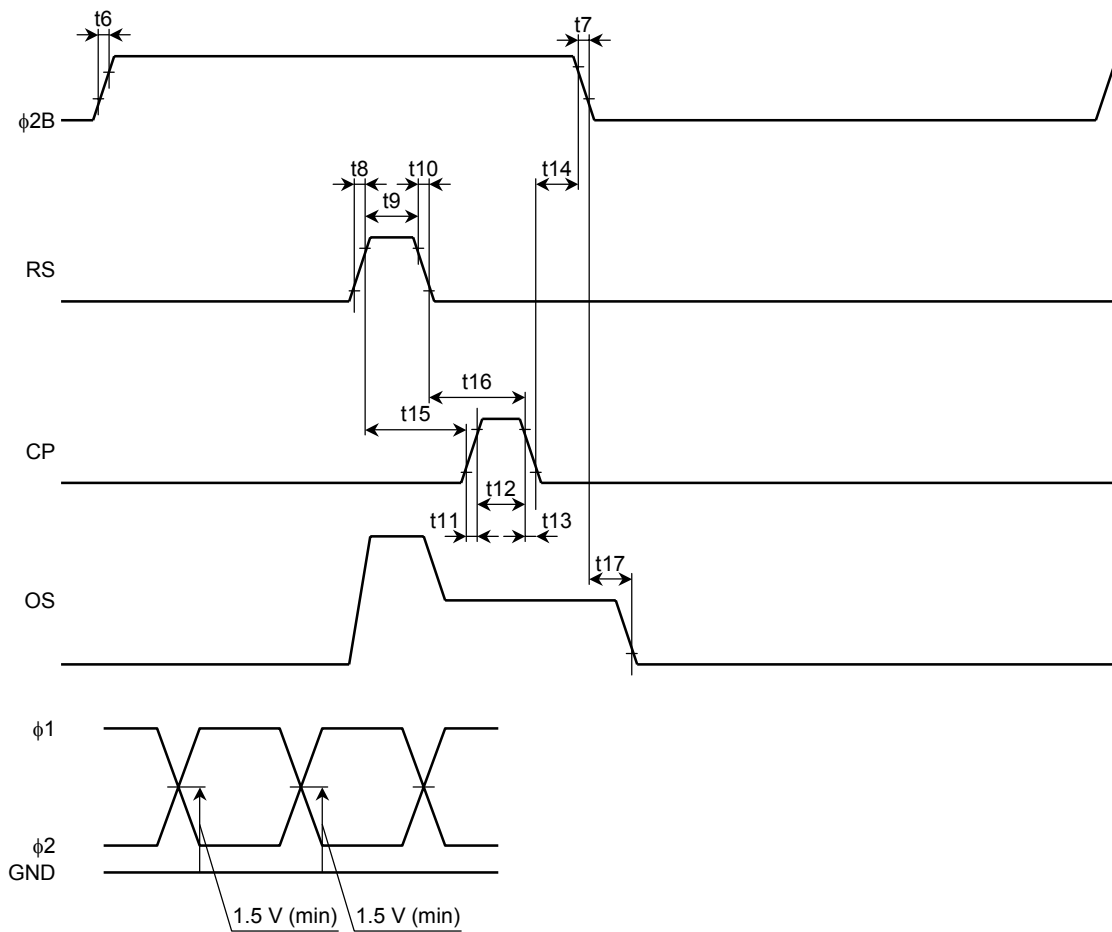
Timing Chart



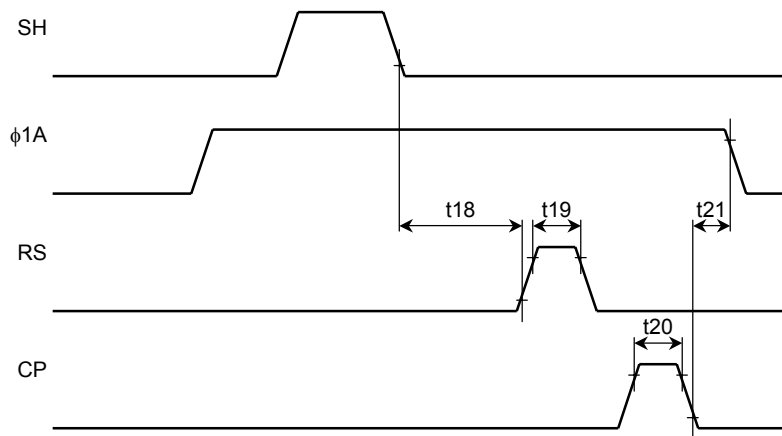
Timing Requirements



Note 13: Hold the RS and CP pins at low during this period.



Timing Requirements (line clamp)

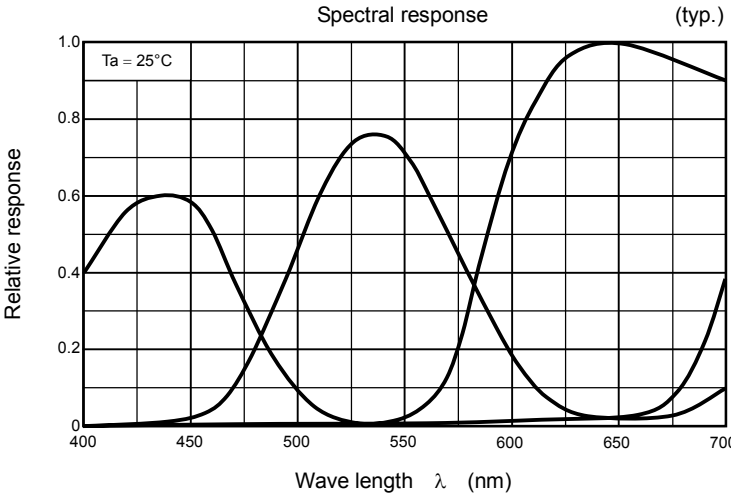


Characteristics	Symbol	Min	Typ. (Note 14)	Max	Unit
Pulse timing of SH and φ1A	t1	60	1000	—	ns
	t5	300	1000	—	ns
SH pulse rise time, fall time	t2, t4	0	50	—	ns
SH pulse width	t3	1000	2000	—	ns
φ1, φ2 Pulse rise time, fall time	t6, t7	0	50	—	ns
RS pulse rise time, fall time	t8, t10	0	20	—	ns
RS pulse width	t9	10	100	—	ns
CP pulse rise time, fall time	t11, t13	0	20	—	ns
CP pulse width	t12	10	100	—	ns
Pulse timing of φ2B and CP	t14	0	40	—	ns
Pulse timing of RS and CP	t15	0	0	—	ns
	t16	10	100	—	ns
Video data delay time (Note 15)	t17	—	10	—	ns
SH, RS pulse timing	t18	300	—	—	ns
RS pulse width (line clamp)	t19	10	—	—	ns
CP pulse width (line clamp)	t20	10	—	—	ns
CP, φ1A pulse timing (line clamp)	t21	5	—	—	ns

Note 14: Measured with $f_{RS} = 1$ MHz.

Note 15: Load resistance is 100 kΩ.

Typical Spectral Response



Caution**1. Electrostatic Breakdown**

The dust and stain on the glass window of the package degrade optical performance of CCD sensor. Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N₂. Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

- a. Prevent the generation of static electricity due to friction by making the work with bare hands or by putting on cotton gloves and non-charging working clothes.
- b. Discharge the static electricity by providing earth plate or earth wire on the floor, door or stand of the work room.
- c. Ground the tools such as soldering iron, radio cutting pliers or pincer.
It is not necessarily required to execute all precaution items for static electricity.
It is all right to mitigate the precautions by confirming that the trouble rate within the prescribed range.

2. Window Glass

The dust and stain on the glass window of the package degrade optical performance of CCD sensor. Keep the glass window clean by saturating a cotton swab in alcohol and lightly wiping the surface, and allow the glass to dry, by blowing with filtered dry N₂. Care should be taken to avoid mechanical or thermal shock because the glass window is easily to damage.

3. Incident Light

CCD sensor is sensitive to infrared light. Note that infrared light component degrades resolution and PRNU of CCD sensor.

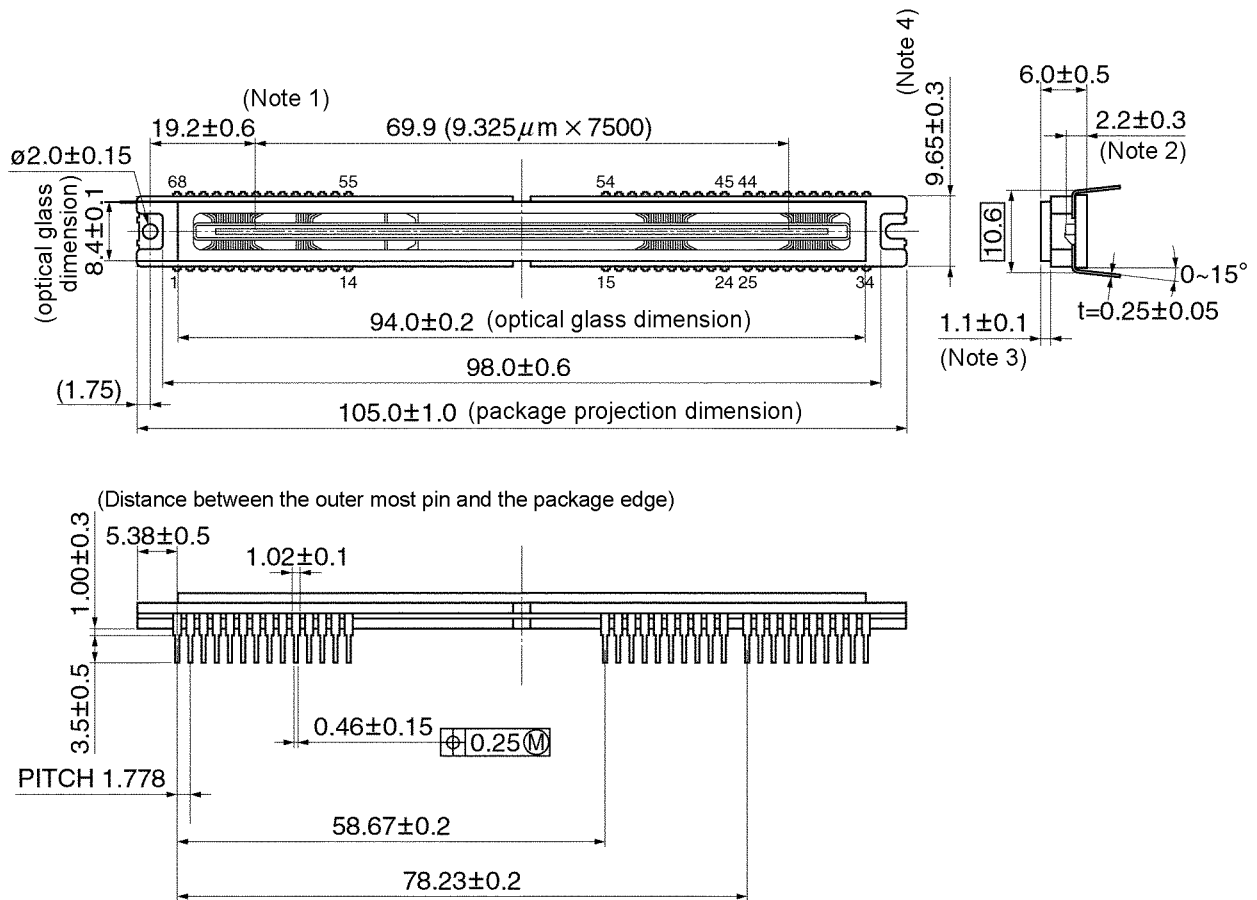
4. Mounting on a PCB

This package is sensitive to mechanical stress.
Toshiba recommends using IC inserters for mounting, instead of using lead forming equipment.

5. Soldering

Soldering by the solder flow method cannot be guaranteed because this method may have deleterious effects on prevention of window glass soiling and heat resistance.
Using a soldering iron, complete soldering within ten seconds for lead temperatures of up to 260°C, or within three seconds for lead temperatures of up to 350°C.

Package Dimensions



- Note 1: Distance between the center of the hole and the first pixel (S1)
- Note 2: Distance between the of the chip and bottom of the package.
- Note 3: Glass thickness (n = 1.5)
- Note 4: Dimensional tolerance is ± 0.3 mm for the 10-mm range from each ceramic edge, ± 0.4 mm for the 10-mm to 27-mm range and ± 0.5 mm for the inner range.

Weight: 16.0 g (typ.)

RESTRICTIONS ON PRODUCT USE

000707EBA

- TOSHIBA is continually working to improve the quality and reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to comply with the standards of safety in making a safe design for the entire system, and to avoid situations in which a malfunction or failure of such TOSHIBA products could cause loss of human life, bodily injury or damage to property.
In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent TOSHIBA products specifications. Also, please keep in mind the precautions and conditions set forth in the "Handling Guide for Semiconductor Devices," or "TOSHIBA Semiconductor Reliability Handbook" etc..
- The TOSHIBA products listed in this document are intended for usage in general electronics applications (computer, personal equipment, office equipment, measuring equipment, industrial robotics, domestic appliances, etc.). These TOSHIBA products are neither intended nor warranted for usage in equipment that requires extraordinarily high quality and/or reliability or a malfunction or failure of which may cause loss of human life or bodily injury ("Unintended Usage"). Unintended Usage include atomic energy control instruments, airplane or spaceship instruments, transportation instruments, traffic signal instruments, combustion control instruments, medical instruments, all types of safety devices, etc.. Unintended Usage of TOSHIBA products listed in this document shall be made at the customer's own risk.
- The products described in this document are subject to the foreign exchange and foreign trade laws.
- The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others.
- The information contained herein is subject to change without notice.